

Notice of References Cited	Application/Control No. 10/594,772	Applicant(s)/Patent Under Reexamination OCHIAI ET AL.	
	Examiner Richard Schnizer, Ph. D.	Art Unit 1635	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Ueda (J. Neurogenetics 15(3-4): 193-204, 2001)
*	V	Nicolas et al (EMBO J. 22(15): 3983-3991, 2003)
*	W	Kennerdell et al (Cell 95: 1017-1026, 1998)
*	X	Ngo et al (PNAS 95: 14687-14692, 1998)

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/594,772		Applicant(s)/Patent Under Reexamination OCHIAI ET AL.	
	Examiner Richard Schnizer, Ph. D.		Art Unit 1635	Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
*	U	Wargelius et al BBRC 263: 156-161, 1999			
	V	Mackenzie et al (App. Env. Microbiol. 66(1): 4655-4661, 2000)			
	W				
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.